


<b>Search Notes</b> 	<b>Application/Control No.</b> 10673698	<b>Applicant(s)/Patent Under Reexamination</b> LEE ET AL.
	<b>Examiner</b> Pich, Ponnoreay	<b>Art Unit</b> 2135

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
See attached EAST notes	3/19/2007	PP

INTERFERENCE SEARCH			
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